

SPECIFICATION

(Reference sheet)

- Supplier : Samsung electro-mechanics
- Product : Multi-layer Ceramic Capacitor

- Samsung P/N : **CL31C221KGFNNNE**
- Description : **CAP, 220pF, 500V, ± 10%, COG, 1206**

A. Samsung Part Number

CL 31 C 221 K G F N N N E
 ① ② ③ ④ ⑤ ⑥ ⑦ ⑧ ⑨ ⑩ ⑪

① Series	Samsung Multi-layer Ceramic Capacitor			
② Size	1206 (inch code)	L: 3.20 ± 0.15 mm	W: 1.60 ± 0.15 mm	
③ Dielectric	COG	⑧ Inner electrode	Ni	
④ Capacitance	220 pF	Termination	Cu	
⑤ Capacitance tolerance	± 10%	Plating	Sn 100% (Pb Free)	
⑥ Rated Voltage	500 V	⑨ Product	Normal	
⑦ Thickness	1.25 ± 0.15 mm	⑩ Special	Reserved for future use	
		⑪ Packaging	Embossed Type, 7" reel	

B. Structure and dimension



Samsung P/N (Lead Free)	Dimension(mm)			
	L	W	T	BW
CL31C221KGFNNNE	3.20 ± 0.15	1.60 ± 0.15	1.25 ± 0.15	0.50 ± 0.30

C. Samsung Reliability Test and Judgement condition

	Performance	Test condition
Capacitance	Within specified tolerance	1MHz±10% / 0.5~5Vrms
Q	1,000 min	
Insulation Resistance	10,000Mohm or 500Mohm× μ F Whichever is smaller	Rated Voltage 60~120 sec.
Appearance	No abnormal exterior appearance	Microscop (X10)
Withstanding Voltage	No dielectric breakdown or mechanical breakdown	150% of the rated voltage
Temperature Characteristics	COG (From -55℃ to 125℃, Capacitance change should be within ±30PPM/℃)	
Adhesive Strength of Termination	No peeling shall be occur on the terminal electrode	500g×F, for 10±1 sec.
Bending Strength	Capacitance change : within ±5% or ±0.5pF whichever is larger	Bending to the limit (1mm) with 1.0mm/sec.
Solderability	More than 75% of terminal surface is to be soldered newly	SnAg3.0Cu0.5 solder 245±5℃, 3±0.3sec. (preheating : 80~120℃ for 10~30sec.)
Resistance to Soldering heat	Capacitance change : within ±2.5% or ±0.25pF whichever is larger Tan δ , IR : initial spec.	Solder pot : 270±5℃, 10±1sec.
Vibration Test	Capacitance change : within ±2.5% or ±0.25pF whichever is larger Tan δ , IR : initial spec.	Amplitude : 1.5mm From 10Hz to 55Hz (return : 1min.) 2hours ´ 3 direction (x, y, z)
High Temperature Resistance	Capacitance change : within ±3% or ±0.3pF whichever is larger Q : 350 min IR : 1,000Mohm or 50Mohm × μ F Whichever is smaller	With 150% of the rated voltage Max. operating temperature 1000+48/-0hrs
Temperature Cycling	Capacitance change : within ±2.5% or ±0.25pF whichever is larger Tan δ , IR : initial spec.	1 cycle condition Min. operating temperature → 25℃ → Max. operating temperature → 25℃ 5 cycle test

※ The reliability test condition can be replaced by the corresponding accelerated test condition.

D. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260+0/-5℃, 10sec. Max)



Product specifications included in the specifications are effective as of March 1, 2013.

Please be advised that they are standard product specifications for reference only.

We may change, modify or discontinue the product specifications without notice at any time.

So, you need to approve the product specifications before placing an order.

Should you have any question regarding the product specifications,

please contact our sales personnel or application engineers.

- Disclaimer & Limitation of Use and Application -

The products listed in this Specification sheet are **NOT** designed and manufactured for any use and applications set forth below.

Please note that any misuse of the products deviating from products specifications or information provided in this Spec sheet may cause serious property damages or personal injury.

We will **NOT** be liable for any damages resulting from any misuse of the products, specifically including using the products for high reliability applications as listed below.

If you have any questions regarding this 'Limitation of Use and Application', you should first contact our sales personnel or application engineers.

- ① Aerospace/Aviation equipment
- ② Automotive or Transportation equipment (vehicles, trains, ships, etc)
- ③ Medical equipment
- ④ Military equipment
- ⑤ Disaster prevention/crime prevention equipment
- ⑥ Any other applications with the same as or similar complexity or reliability to the applications set forth above.